

System Overview

Description	Model			S	erial Number
CCD Head ∇	D U 9	34P -	BR-DI) (CD-16346
TE Cooler performance (~)		1	High	Ultra-high ✓
Accessories	Power Sup	oply Unit (PS	-24)		PS -25
					•
	SO-	LM-		MFL-	
Serial/Batch Number					
Other					

^{abla} Sensor types are defined in Table 1 using the last two letters in box Model Number.

CCD Details

20 100m204 7.P			Serial Number	
E2V	CCD47-10	1024x1024, 13μm x 13μm	12262-10-09	
E2V	CCD57-10	512x512, (FT), 13μm x 13μm		
E2V	CCD77-00	512x512, 24μm x 24μm		

Special Feature	(~)		(~)
NIMO	~	AR coated Window (½º wedge)	~
Fringe Suppression	y	Custom Cables	
Shielded Anti-Blooming		Custom Mounting Flange	
MgF ₂ Input			***************************************

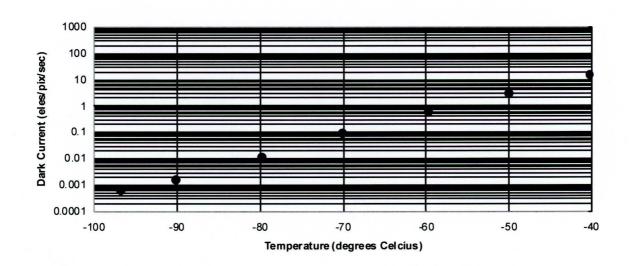


Summary of System Test Data

Readout Noise +1 and Base Mean Level

A/D Rate	Preamp	CCD	Single Pixel	Full Vert Bin	Base Level ◆2
(MHz All 16 bit)	setting	Sensitivity ◆3	Noise	Noise	(Counts)
All 10 bit)		eles per A/D count	electrons	electrons	
5	x1	6.5	34.5	34.1	1079
5	x2	3.0	18.7	20.8	1725
5	x4	1.6	15.9	15.1	3169
3	x1	5.7	19.2	19.2	1195
3	x2	3.0	13.2	14.8	2255
3	x4	1.3	10.6	11.9	4099
1	x1	5.4	11.3	10.9	959
1	x2	2.7	8.0	7.9	1933
1	x4	1.2	6.3	6.1	3939
0.05	x1	5.2	4.9	4.9	549
0.05	x2	2.8	4.0	4.1	1501
0.05	x4	1.2	3.4	3.4	3464
Satura	tion Signal p	er pixel	120022	Electror	ns/pixel

CCD Dark Current



Minimum Dark Current Achievable ◆4	0.00069	electro	ns/pixel/s	ес
@ Sensor Temperature of ◆5	-96.77	°C	16	°C cooling Water
		With PS	-25	
CCD Dark Current Uniformity better than ◆6	0.2742	electro	ns/pixel/s	ec



Linearity and Uniformity

Linearity better than ◆7	1	% over 16 bits	
Response Uniformity better than ◆8	1.75	%	

Response Defects

White/Bl	ack Spot	s • 9)			(X,Y)
Cer	Centroid		Number of Pixels Centro		id	Number of Pixels
(X ((((((((((((((((((, X		X)	
White/Bla		,	Column nun	nbers indicated	X	X X
Trap ◆11	1			(X,Y)	(X	, X

Dark Current Defects

Hot Spots ◆12			(X,Y)
Centroid	Number of Pixels	Centroid	Number of Pixels
(X , X) (,) (,) (,) (,)	X		
Hot Columns •1	3 Column numl	bers indicated	x x



Test Conditions

Readout Noise tested at	-80	°C with	16	°C water
Base Mean Level measured at	-80	°C with	16	°C water
Dark Current Uniformity tested at	-65	°C with	16	°C water
Blemishes tested at	-65	°C with	16	°C water

Custom Testing

Signed System Passed for Shipping
Date

C.KELZ

System Passed for Shipping

5™ FEBRUARY 2014

Hardware	HEADBOARD	FPGA
Version #	AB	20.24
Shipping Software	SOLIS	SDK
Version #		
Testing Software	SOLIS	SDK
Version #	4.24.30004.0	2.96.30004.0

${\it V}$ Table 1; Key code to define the meanings of the last two letters in the Model Number

Sensor Options						
OE	Open electrode	BU2	Back Illuminated (BI) + 250nm UV optimised			
FI	Front illuminated (FI)	BU	BI + UV (350nm) optimised			
UV	FI+UV coating	BV	BI + VIS (550nm) optimised)			
FO	FI + Fibre optic	BR-DD	BI + NIR +deepdepletion			
FI-DD	FI + deep depletion	BN	BI with no AR coating			



Performance Notes

- Readout Noise is measured for both single pixel (SP) and fully vertically binned (FVB) with the CCD in darkness at temperature indicated and minimum exposure time. Noise values will change with pre-amplifier gain selection [PAG].
- ♦2 Average electronic DC offset for CCD in darkness at temperature indicated and minimum exposure time under dark conditions measured by single pixel (SP) for imaging systems and by (FVB) for spectroscopic systems.
- ◆3 Sensitivity is calculated in photoelectrons per A/D count from measurements of the Photon Transfer Curve.
- Dark current falls exponentially with temperature. However, for a given temperature the actual dark current can vary by more than an order of magnitude from device to device. The devices are specified in terms of minimum dark current achievable rather than minimum temperature.
- ◆5 Minimum temperature achieved for thermoelectric (TE) cooler set to maximum value with water cooling
- RMS (root mean square) deviation of dark current for fully binned operation for spectroscopic cameras, or full resolution image for imaging cameras, under dark conditions at temperature indicated (pixel/column defects not included). This variation is mainly cosmetic since it is fully subtractable without significant loss of performance.
- ◆7 Linearity is measured from a plot of Counts vs. Signal over the 16 bit dynamic range. Linearity is expressed as a %age deviation from a straight line fit. This quantity is not measured on individual systems.
- RMS (root mean square) deviation from the average response of the CCD in full resolution image for imaging cameras, illuminated with uniform white light (defects not included).
- •9 White/black pixels have signals >25% above/below the average (25% contrast) with uniform illumination across the sensor.
- ◆10 A black column is defined as having ≥ 10 black pixels for imaging cameras.
- ◆11 Pixels which absorb charge as it is clocked through the defective area. When the light source is switched off, the signal from the trap appears to drop off more slowly than the signal from the surrounding pixels.
- ♦12 Hot spots are counted if they exhibit >50 times the maximum specified dark current at the test temperature indicated.
- ♦13 A column is considered defective if >10 pixels are affected, or if the column exhibits >2 times the maximum specified dark current at the test temperature indicated.